

40 V, 12 mOhm bi-directional Gallium Nitride (GaN) FET in a1.2 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)12 March 2025Product data sheet

1. General description

The GANB012-040CBA is a 40 V, 12 m Ω bi-directional Gallium Nitride (GaN) High Electron-Mobility-Transistor (HEMT) in a Wafer Level Chip-Scale (WLCSP) package. It is a normally-off e-mode device offering superior performance.

2. Features and benefits

- · Enhancement mode normally-off power switch
- Bi-directional device
- Ultra high switching speed capability
- Ultra-low on-state resistance
- RoHS, Pb-free, REACH-compliant
- High efficiency and high power density
- Wafer Level Chip-Scale Package (WLCSP) 1.2 mm x 1.7 mm

3. Applications

- High-side load switch
- OVP protection in smart phone USB port
- Power switch circuits
- Stand-by power system

4. Quick reference data

Table 1. Quick	reference data						
Symbol	Parameter	Conditions		Min	Тур	Мах	Unit
V _{DD}	drain-drain voltage	-40 °C ≤ T _j ≤ 125 °C	[1]	-	-	40	V
ID	drain current	V _{GD} = 5 V; T _{mb} = 25 °C	[2][3]	-	-	10	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 1</u>		-	-	11	W
Tj	junction temperature			-40	-	125	°C
Static characte	eristics						
R _{DDon}	drain-drain on-state resistance	$V_{GD2} = 5 V; V; I_{D1} = 10 A; T_j = 25 °C;$ Fig. 9; Fig. 10; Fig. 11	[1]	-	9	12	mΩ
		V _{GD2} = 5 V; V; I _{D1} = 10 A; T _j = 125 °C; Fig. 9; Fig. 12	[1]	-	16.5	-	mΩ

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Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Dynamic chara	cteristics						
Q _{G(tot)}	total gate charge	$\begin{split} I_{D} &= 10 \text{ A}; V_{DS} = 20 V; V_{GS} = 5 V; \\ T_{j} &= 25 ^\circ\text{C}; \underline{\text{Fig. 13}}; \underline{\text{Fig. 14}} \end{split}$	[2]	-	7.2	-	nC

[1] Parameters are understood to apply for either polarity of bias. For example, V_{DD} is the same whether D1 is the source and D2 is the drain or vice versa.

[2] D1 and D2 are symetrical with respect to the gate, G. Either can take the function of source or drain. For datasheet parameters, the source is defined as the terminal, D1 or D2, which has lower potential in the test circuit. The drain is the terminal with the higher potential.

[3] Limited by solder ball

5. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
B2-B3, D1-D3	D1	drain1	1 2 3	
A1-A3, C2-C3	D2	drain2		D1
B1, C1	G	gate	B C D Transparent top view WLCSP12_SOT8088	G D2 aaa-037587

6. Ordering information

Table 3. Ordering information

Type number	Package	Package						
	Name	Description	Version					
GANB012-040CBA	WLCSP12_SOT8088	WLCSP12, 1.2 mm x 1.7 mm	WLCSP12_SOT8088					

7. Marking

Table 4. Marking codes Type number Marking code GANB012-040CBA 012ACBA

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8. Limiting values

Table 5. Limiting values

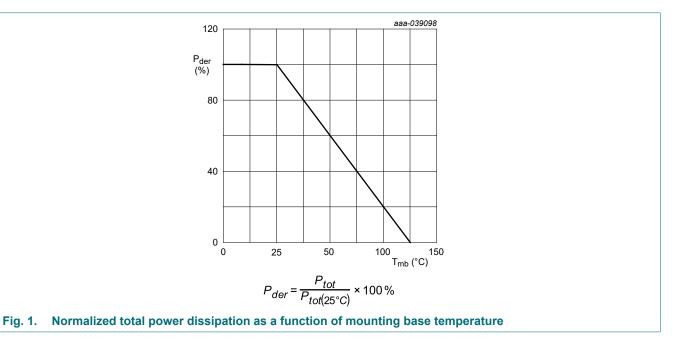
In accordance with the Absolute Maximum Rating System (IEC 60134). T_i = 25 °C unless otherwise stated.

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DD}	drain-drain voltage	-40 °C ≤ T _j ≤ 125 °C	[1]	-	40	V
V _{DG}	drain-gate voltage		[1]	-	40	V
V _{GD}	gate-drain voltage		[1]	-	6	V
I _D	drain current	V _{GD} = 5 V; T _{mb} = 25 °C	[2] [3]	-	10	А
I _{DM}	peak drain current	pulsed; $t_p \le 300 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$; Fig. 2	[2] [3]	-	50	А
P _(tot)	total power dissipation	T _{mb} = 25 °C; <u>Fig. 1</u>		-	11	W
T _{stg}	storage temperature			-40	150	°C
Tj	junction temperature			-40	125	°C
T _{sld(M)}	peak soldering temperature			-	260	°C

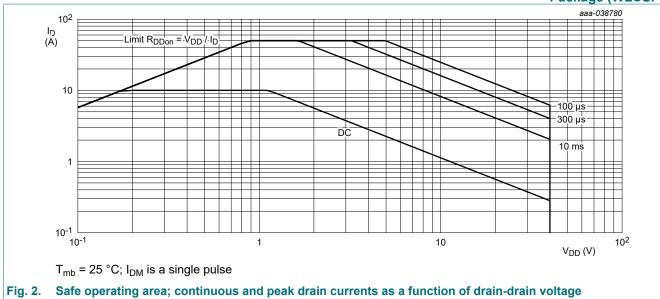
[1] Parameters are understood to apply for either polarity of bias. For example, V_{DD} is the same whether D1 is the source and D2 is the drain or vice versa.

[2] D1 and D2 are symetrical with respect to the gate, G. Either can take the function of source or drain. For datasheet parameters, the source is defined as the terminal, D1 or D2, which has lower potential in the test circuit. The drain is the terminal with the higher potential.

[3] Limited by solder ball.



40 V, 12 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.2 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)



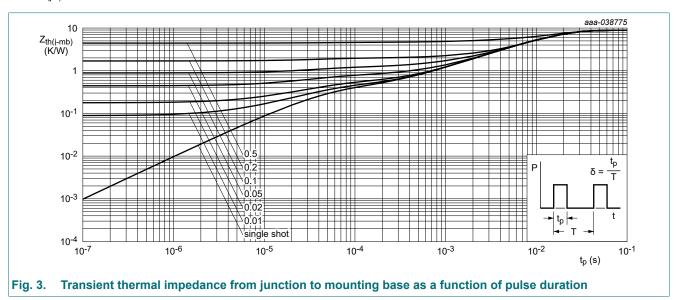
9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Тур	Мах	Unit
R _{th(j-c)}	thermal resistance from junction to case		[1]	-	-	1.4	K/W
R _{th(j-mb)}	thermal resistance from junction to mounting base	<u>Fig. 3</u>		-	-	8.88	K/W
R _{th(j-a)}	thermal resistance from junction to ambient		[2]	-	-	67.35	K/W

[1] Thermal junction to top side of package.

[2] R_{th(j-a)} is determined with the device mounted on one square inch of copper pad single layer 2 oz copper on FR4 board.



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10. Characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static cha	racteristics	1					
BV _{DDS}	drain-drain breakdown voltage	I_{D1D2} = 500 µA; V_{D2} = V_G = 0 V; T_j = 25 °C	[1]	40	-	-	V
V _{GD(th)}	gate-drain threshold voltage	$I_D = 1 \text{ mA}; V_{D1} = 0 \text{ V}; V_{D2} = V_G; T_j = 25 \text{ °C};$ Fig. 8	[1]	0.8	1.35	2.4	V
		$I_D = 1 \text{ mA}; V_{D1} = 0 \text{ V}; V_{D2} = V_G; T_j = 125 \text{ °C};$ Fig. 8		-	1.1	-	V
I _{DDS}	drain-drain leakage current	V _{DD} = 40 V; V _{GD} = 0 V; T _j = 25 °C	[1]	-	0.1	20	μA
I _{GDS}	gate-drain leakage	V _{GD} = 5 V; V _{DD} = 0 V; T _j = 25 °C	[1]	-	0.5	5	μA
	current	V _{GD} = -5 V; V _{DD} = 0 V; T _j = 25 °C	[2]	-30	-	-	μA
		V _{GD} = 6 V; V _{DD} = 0 V; T _j = 25 °C		-	5	30	μA
		V _{GD} = -6 V; V _{DD} = 0 V; T _j = 25 °C		-40	-	-	μA
		V _{GD} = 5 V; V _{DD} = 0 V; T _j = 85 °C	[1]	-	0.5	5	μA
		V _{GD} = -5 V; V _{DD} = 0 V; T _j = 85 °C		-30	-	-	μA
		V _{GD} = 6 V; V _{DD} = 0 V; T _j = 85 °C		-	5	30	μA
		V _{GD} = -6 V; V _{DD} = 0 V; T _j = 85 °C		-40	-	-	μA
R_{DDon}	drain-drain on-state resistance	V _{GD2} = 5 V; I _{D1} = 10 A; T _j = 25 °C; <u>Fig. 9;</u> <u>Fig. 10; Fig. 11</u>	[1]	-	9	12	mΩ
		V _{GD2} = 5 V; I _{D1} = 10 A; T _j = 125 °C; <u>Fig. 9;</u> <u>Fig. 12</u>		-	16.5	-	mΩ
R _G	gate resistance	f = 1 MHz; T _j = 25 °C	[1]	-	3	-	Ω
Dynamic o	haracteristics						
Q _{G(tot)}	total gate charge	V_{DS} = 20 V; V_{GS} = 5 V; I_D = 10 A; T_j = 25 °C;	[3]	-	7.2	-	nC
Q _{GS}	gate-source charge	Fig. 13; Fig. 14		-	0.9	-	nC
Q _{GD}	gate-drain charge			-	3.9	-	nC
C _{iss}	input capacitance	$V_{DS} = 20 V; V_{GS} = 0 V; f = 1 MHz; T_j = 25 °C;$	[3]	-	405	-	pF
C _{oss}	output capacitance	Fig. 15		-	174	-	pF
C _{rss}	reverse transfer capacitance			-	104	-	pF
Q _{oss}	output charge	V _{DS} = 20 V; V _{GS} = 0 V; T _i = 25 °C; <u>Fig. 7</u>	[3][4]	-	5.6	-	nC

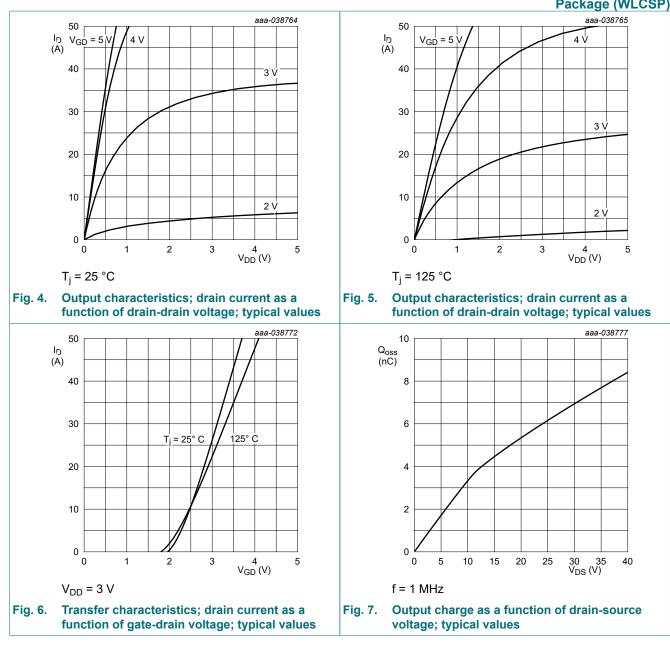
[1] Parameters are understood to apply for either polarity of bias. For example, V_{DD} is the same whether D1 is the source and D2 is the drain or vice versa.

[2] Specification is validated during qualification at 25°C only

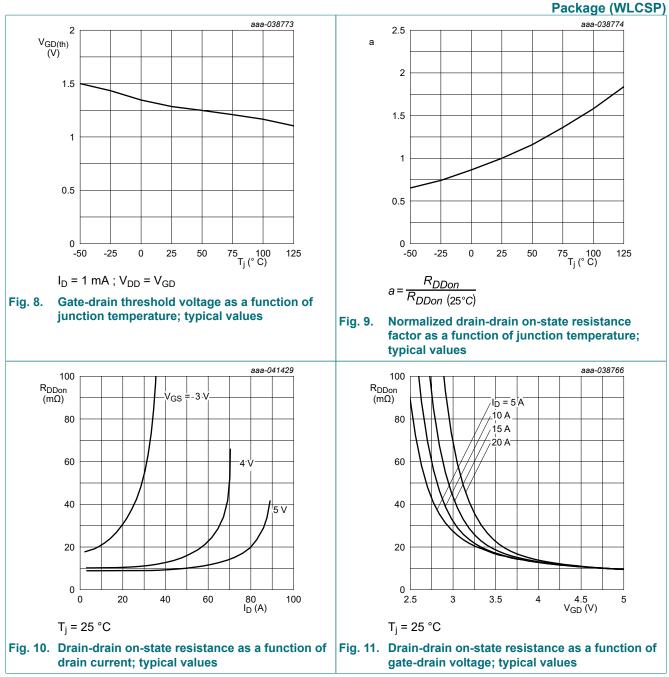
[3] D1 and D2 are symetrical with respect to the gate, G. Either can take the function of source or drain. For datasheet parameters, the source is defined as the terminal, D1 or D2, which has lower potential in the test circuit. The drain is the terminal with the higher potential.

[4] Q_r is not specified separately from Q_{oss} for e-mode GaN FETs, since Q_r = Q_{oss} + Q_D, and Q_D = 0. (Q_D is charge associated with diffusion of minority carriers. Since there is no body diode, no minority carriers in excess of Q_{oss} have to be transferred for e-mode GaN FETs.)

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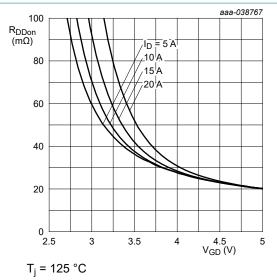


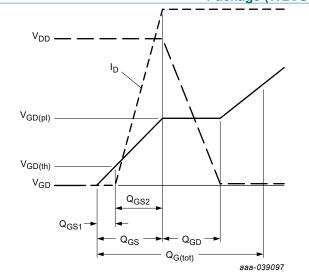
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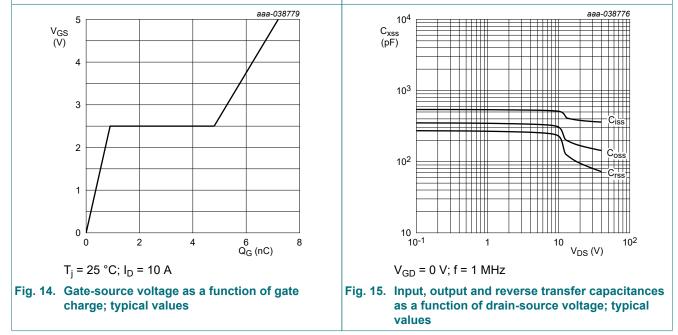
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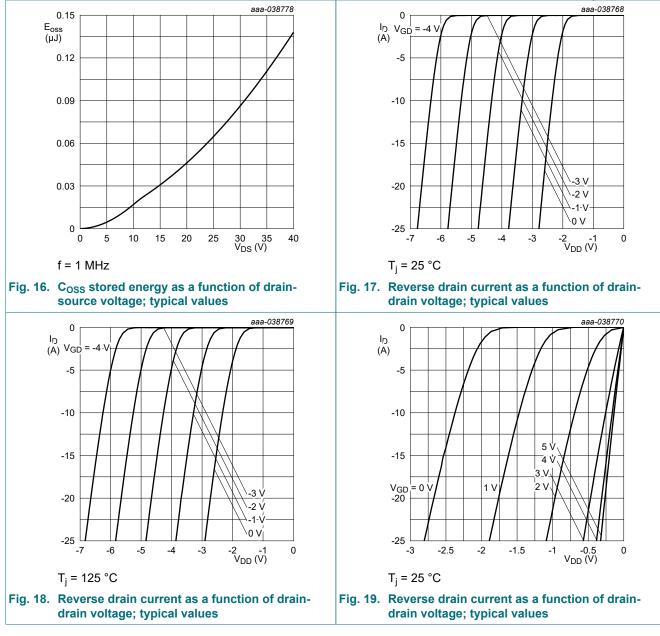




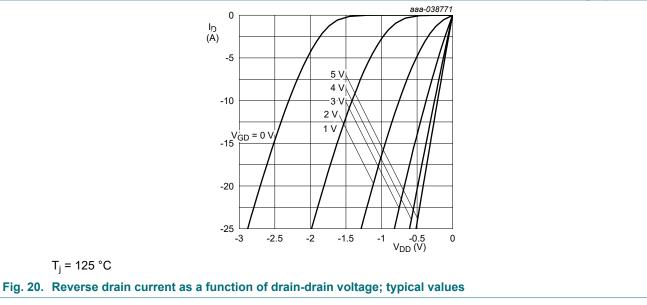


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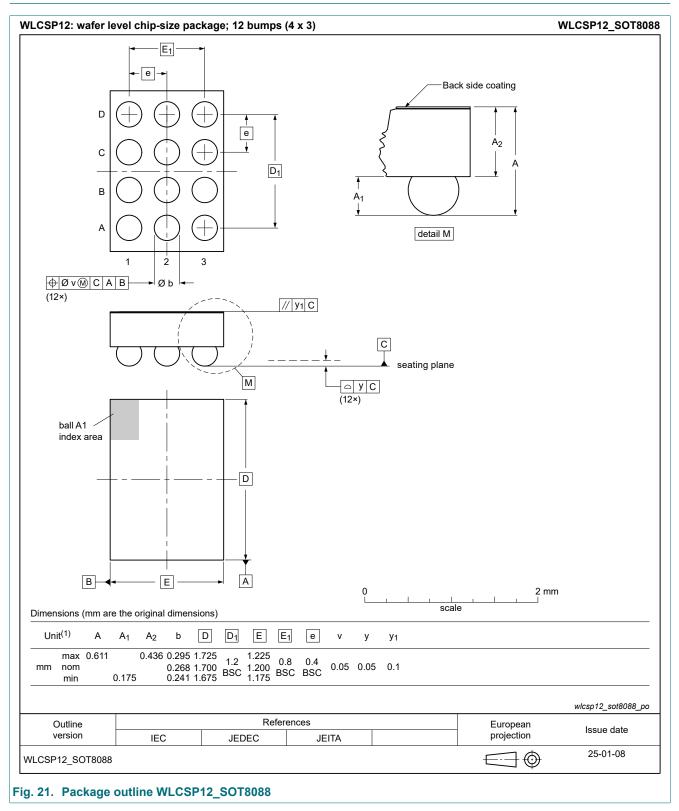


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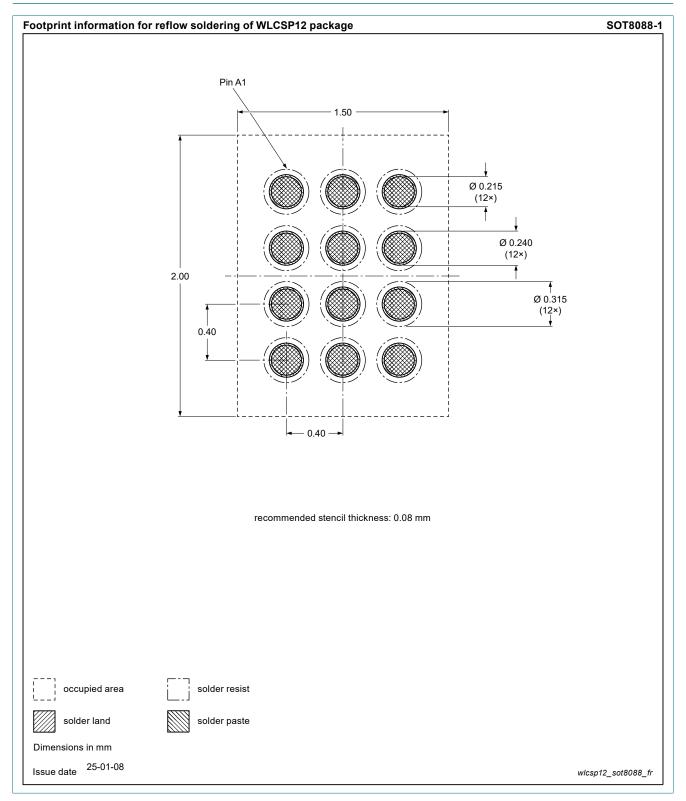
11. Package outline



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40 V, 12 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.2 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

12. Soldering



40 V, 12 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.2 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

13. Legal information

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Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

 Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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